

Notice of References Cited	Application/Control No. 10/083,991	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,728,621	03-1998	Zheng et al.	438/427
*	C	US-6,287,174	09-2001	Detzel et al.	451/41
*	D	US-6,461,932	10-2002	Wang, Fu-Cheng	438/400
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*	F	US-6,171,962	01-2001	Karlsson et al.	438/692
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